


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585755	<b>Applicant(s)/Patent Under Reexamination</b>  PARK ET AL.
	<b>Examiner</b>  YUWEN PAN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	82, 83, 551, 552.1, 553.1	12/15/10	YP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search	12/15/10	YP
updated search	6/6/2011	YP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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